,	S	е	•	3	ı	7	C	h	I	V	(0	ĺ	ϵ	S



Application/Control No.	Applicant(s)/Patent under Reexamination						
10/608,193	NIKIEL ET AL.						
Examiner	Art Unit						
Hanh B. Thai	2163						

	SEAR	CHED	
Class	Subclass	Date	Examiner
707	104.1, 205	11/9/2006	нт
709	235	11/9/2006	нт
711	114, 170	11/9/2006	нт
			•

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
707	104.1	11/9/2006	нт			
711	114, 170	11/9/2006	нт			
		, , ,				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)						
	DATE	EXMR				
East search (updated text search)	11/9/2006	нт				
IEEE search Google ACM SiteSeer	11/9/2006	нт				
Consulted: Alford Kindred (Primary 707) Tod Swann (101)	11/9/2006	нт				
		,				
		,				